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EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY		CLASS	SUBCLASS	Translation Yes No
Ku	JP10144225	05/29/1998	JAPAN(Full Japanese Text)				Abst.
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du	JP 11288666	10/19/1999	JAPAN(Full Japanese Text)				Abst. only
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.